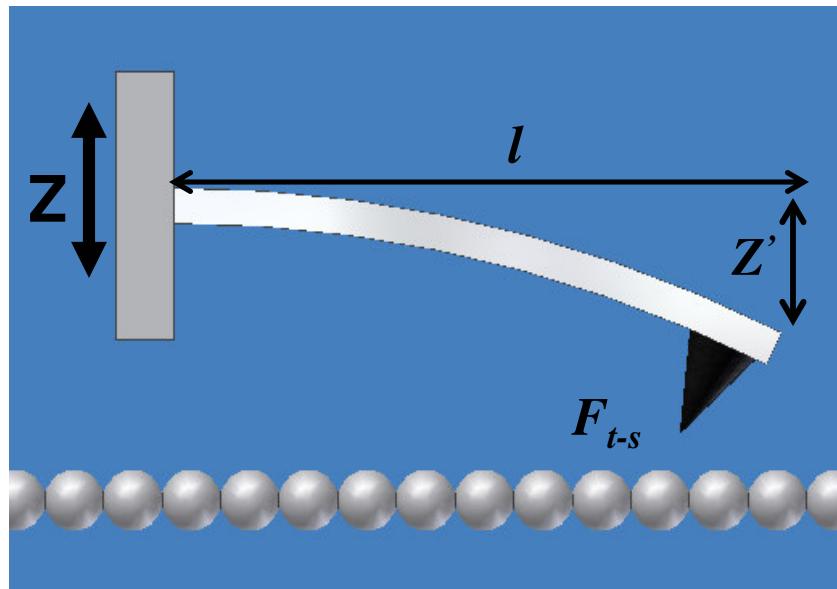


# Tuning Fork FM-AFM

# AFM-Fundamental Concepts



## Atomic Force Microscopy (AFM)

- Tip-surface interaction ( $F_{t-s}$ ) causes deflection of cantilever
- Measure deflection ( $z'$ )
  - STM
  - Optically
  - Self sensing
    - Piezoelectric
    - Piezoresistive
- Deflection proportional to tip-surface force (beam equation)

$$z' = -\frac{l^3}{3EI} F_{t-s}$$

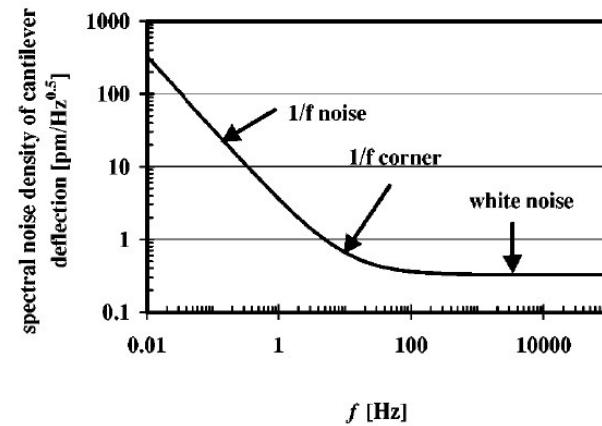
- Scan across surface while adjusting Z

# AFM-Classification

- Static
  - Measure deflection
  - Shown earlier
- Dynamic
  - Deliberately oscillate cantilever
  - Measure changes to amplitude, frequency, and/or phase caused by tip-sample interaction
  - Amplitude Modulation (AM)
    - Maintain driving frequency and driving amplitude
    - Measure cantilever amplitude changes
  - Frequency Modulation (FM)
    - Actively maintain cantilever amplitude
    - Measure cantilever frequency shift

# Why FM-AFM?

- Static
  - $1/f$  noise
  - Scan rate versus force sensitivity
    - Small  $k$  for high sensitivity
    - Large  $k$  for higher scan rate (bandwidth)
- Dynamic
  - Shift away from dc
  - AM-AFM
    - Slow transient decay
  - FM-AFM
    - Rapid change in natural frequency



$$k = 3 \frac{EI}{l^3} \Rightarrow z' = \left( \frac{1}{k} \right) F_{t-s}$$

$$f_0 = \frac{1}{2\pi} \sqrt{\frac{k}{m_{eff}}} \quad \text{need } f_0 \gg (BW)$$

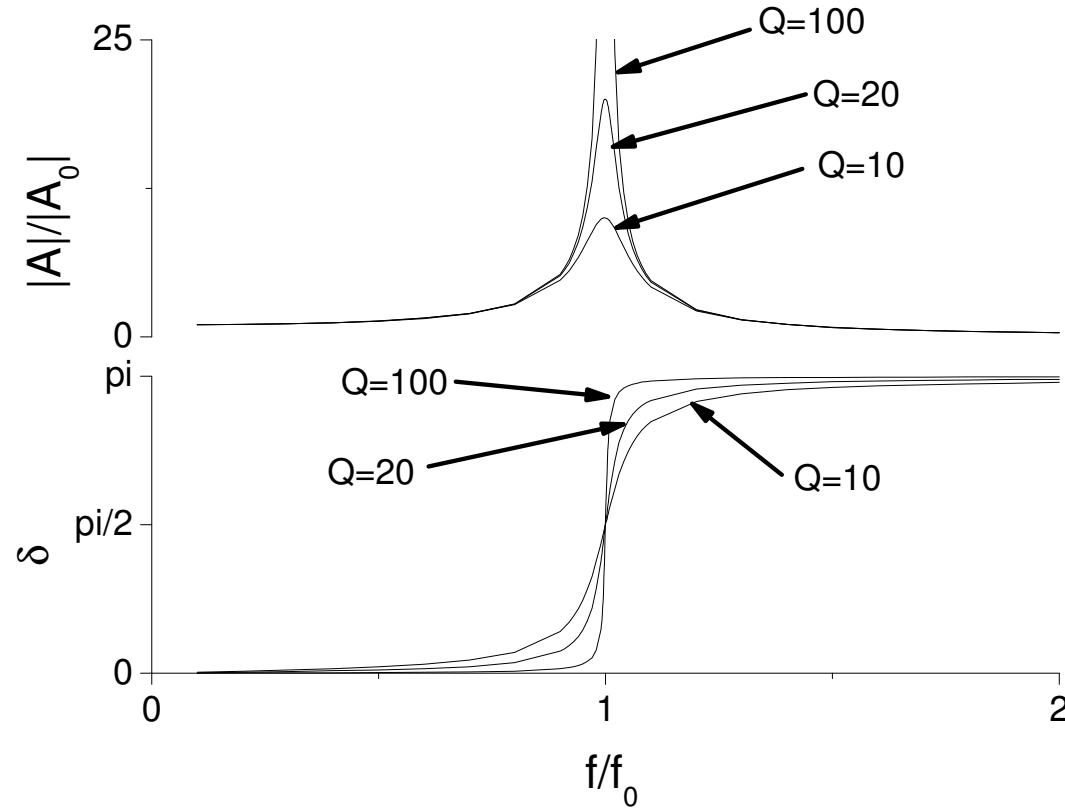
$$\tau_{AM} \approx 2Q/f_0$$

$$\tau_{FM} \approx 1/f_0$$

However, all offer atomic resolution

# Cantilever Model

- Consider cantilever as damped, harmonic oscillator with sinusoidal driving force
- Phase,  $\delta$ , is difference between driving force and resultant cantilever oscillation



$$\ddot{x} + 2\beta\dot{x} + \omega_0^2 x = A_{drive} \cos(\omega t)$$

$$|A| = \frac{|A_{drive}|}{\sqrt{(1 - f_{drive}^2/f_0^2) + f_{drive}^2/(f_0^2 Q)}}$$

$$\delta = \tan^{-1} \left( \frac{f_{drive}}{Q f_0 (1 - f_{drive}^2/f_0^2)} \right)$$

# Tip-Surface Interaction

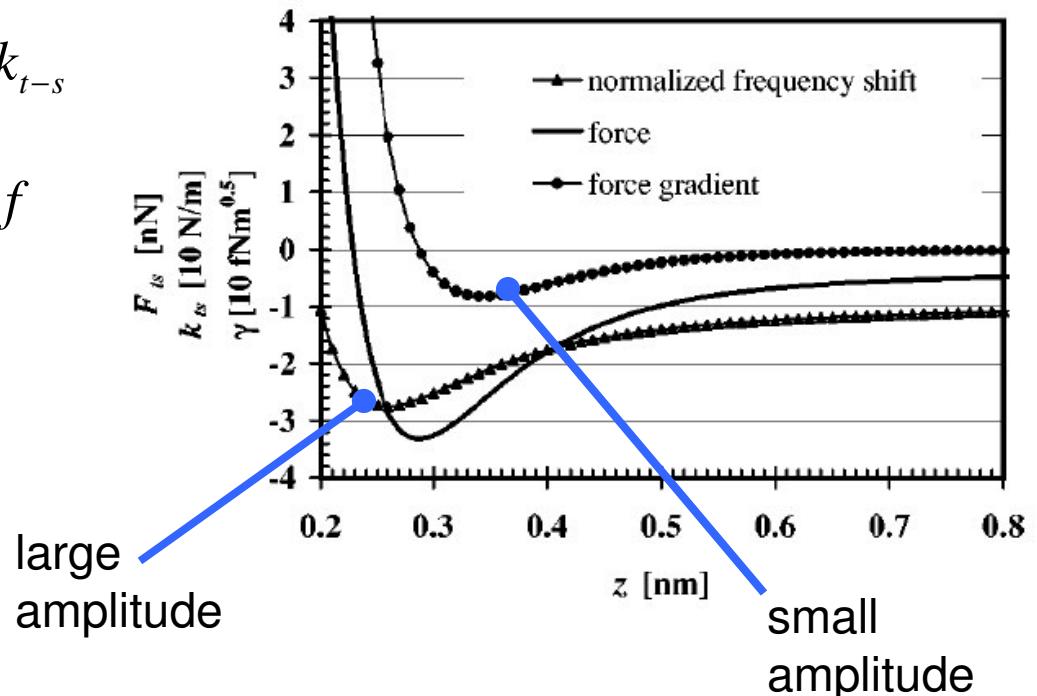
- Cause of tip-sample force,  $F_{ts}$ ,
  - Van der Waal
  - Chemical
  - Electrostatic
- Force between tip and sample causes a change in the natural frequency

$$k_{ts} = -\partial F_{ts}/\partial z \rightarrow k^* = k + k_{ts}$$

$$f = \frac{1}{2\pi} \sqrt{\frac{k^*}{m_{eff}}} \rightarrow f = f_0 + \Delta f$$

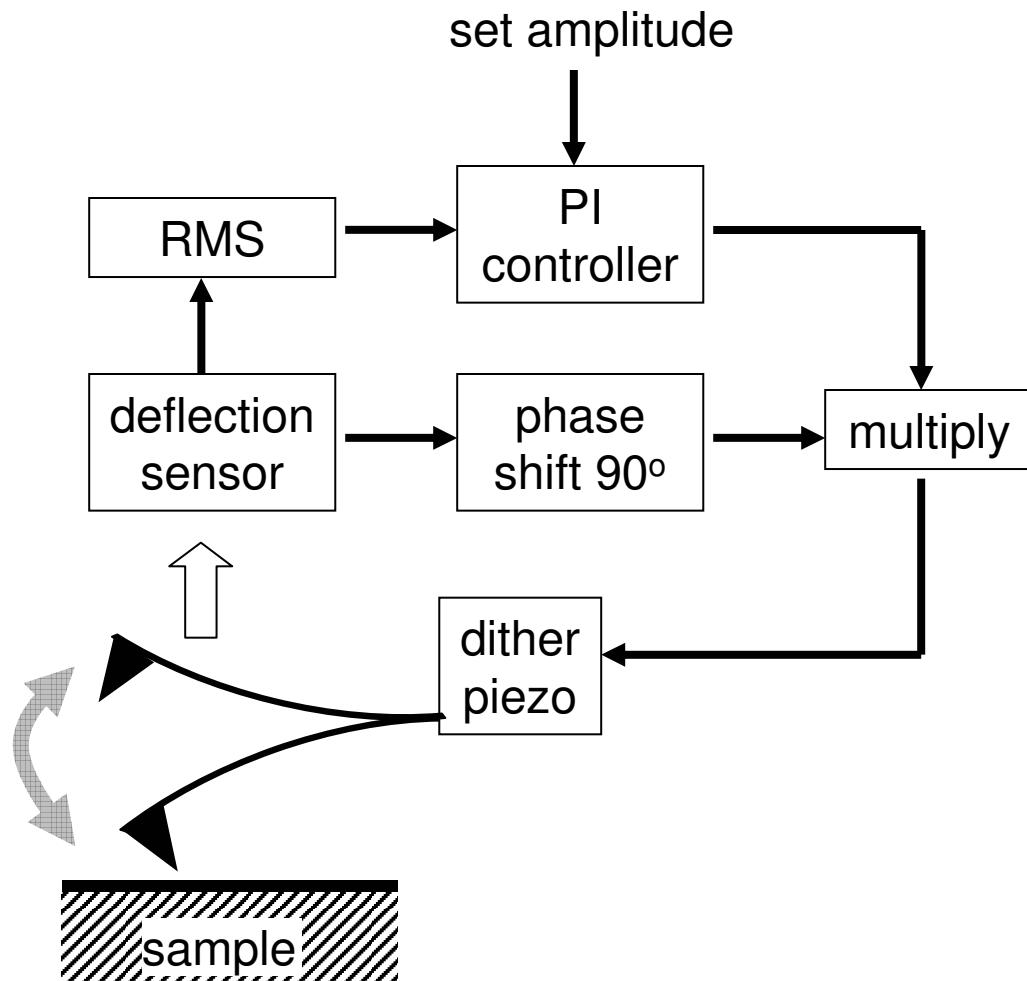
$$\Delta f = -\frac{f_0}{kA^2} \langle F_{ts} q' \rangle$$

$$\gamma \equiv \frac{kA^{3/2}}{f_0} \Delta f$$

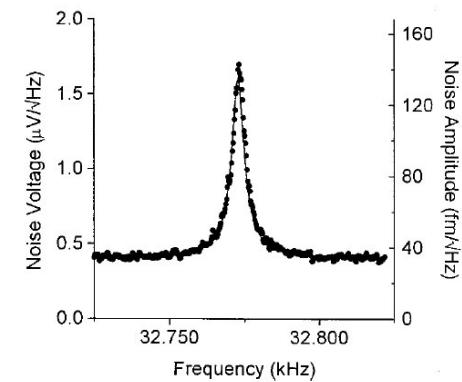


# Experimental Set-Up

## Mechanical Excitation



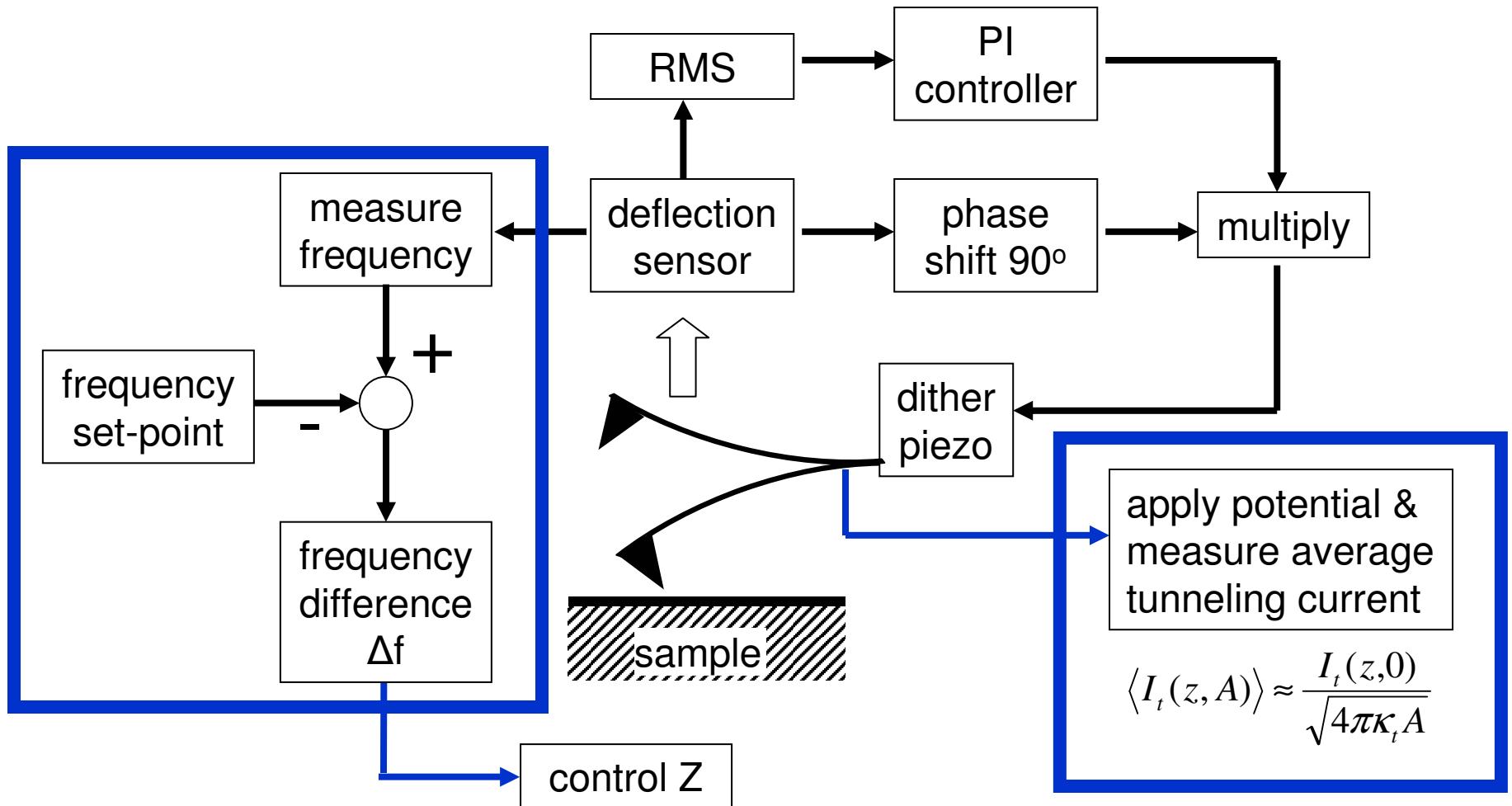
But what gets it started?



$$\frac{1}{2}k\langle z_{th}^2 \rangle = \frac{1}{2}k_b T$$

# Experimental Set-Up

## Mechanical Excitation



# Experimental Set-Up

## Tuning Fork & Electrical Excitation

EE eliminates:

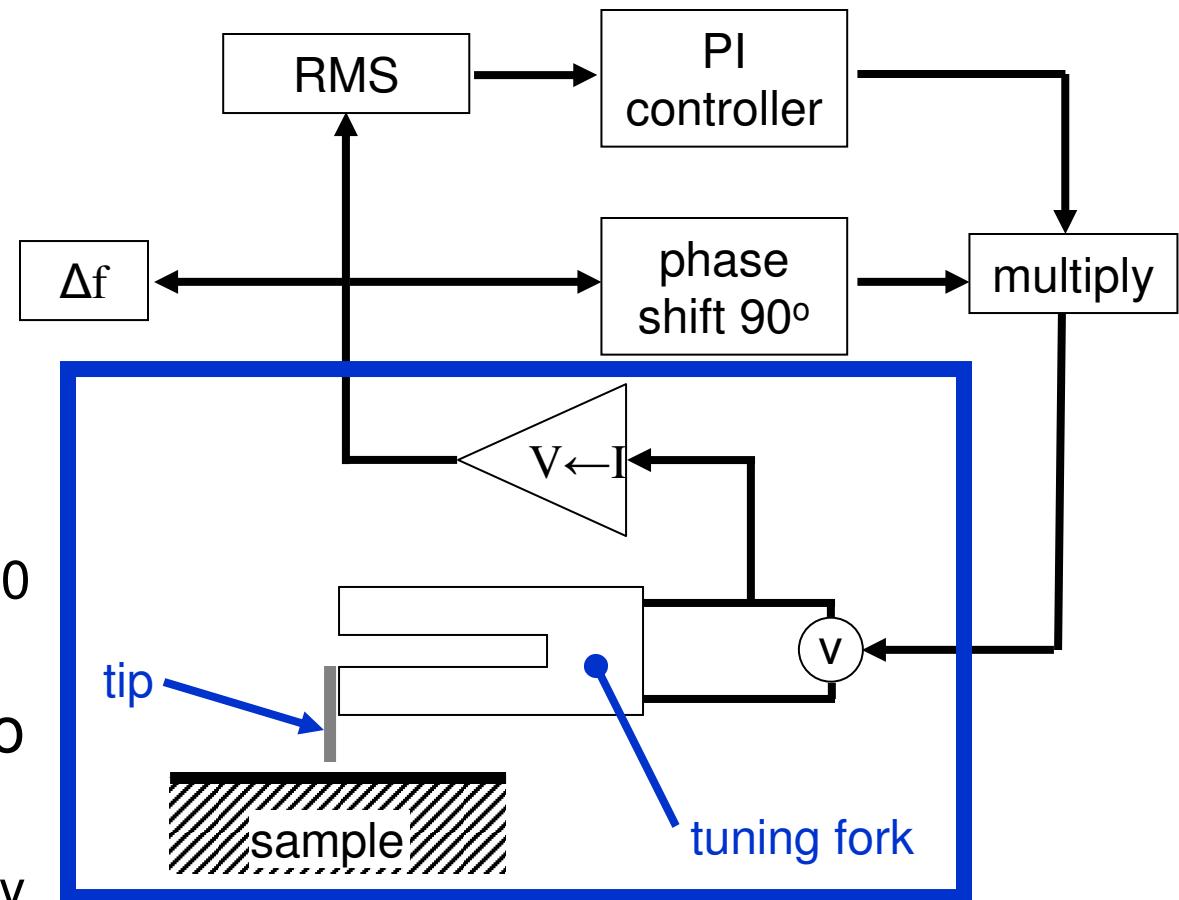
- dither piezo
- deflection sensor

TF enhances:

- Q from  $\sim 100 \rightarrow \sim 10,000$   
(S/N increases)

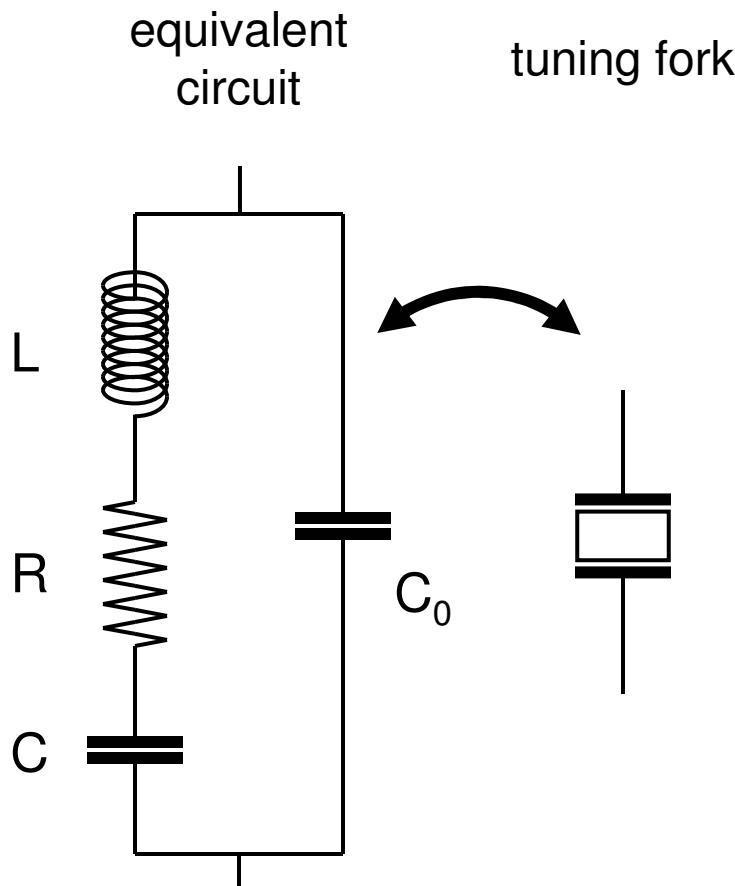
Quartz vs. other piezo

- Low dissipation
- High-frequency stability

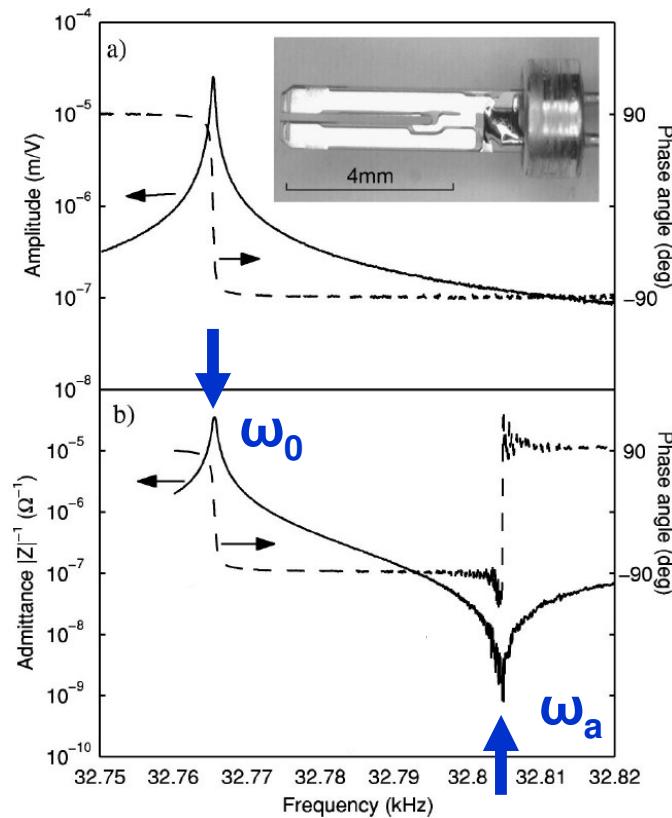


# Experimental Set-Up

## Electrical Excitation



$L=8.1\text{e}3\text{H}$ ,  $R=27\text{k}\Omega$ ,  $C=2.9\text{fF}$ ,  $C_0=1.2\text{pF}$

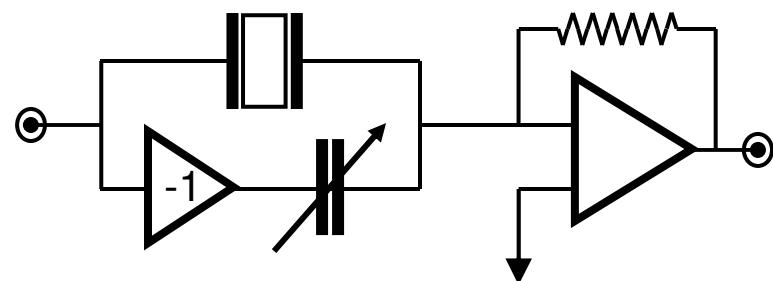
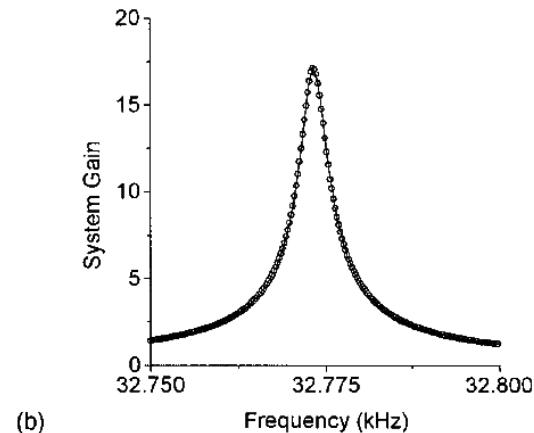
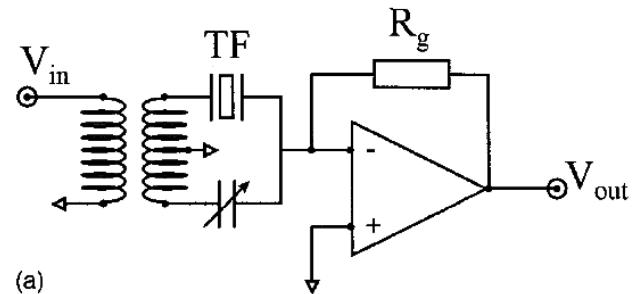
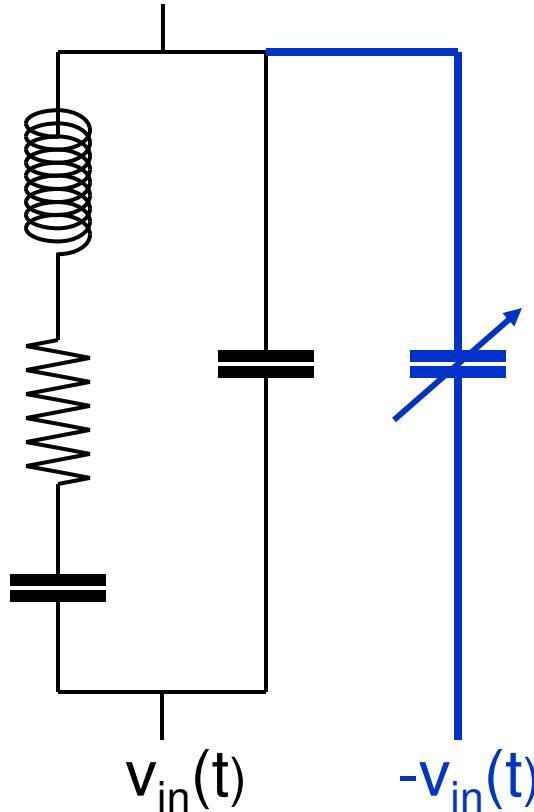


$$\omega_0 = 1/\sqrt{LC}$$

$$\omega_a = \omega_0 \sqrt{1 + C/C_0}$$

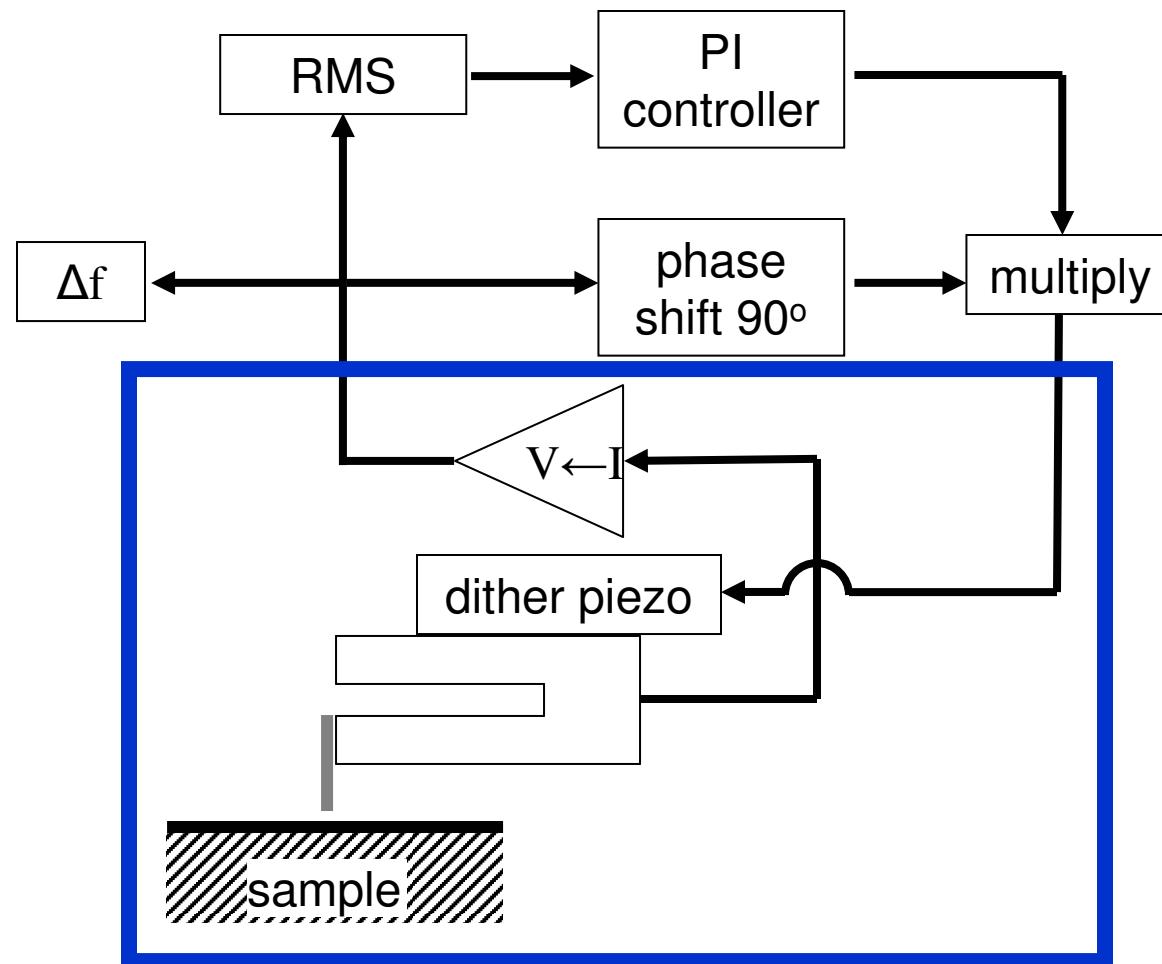
# Experimental Set-Up

## Electrical Excitation



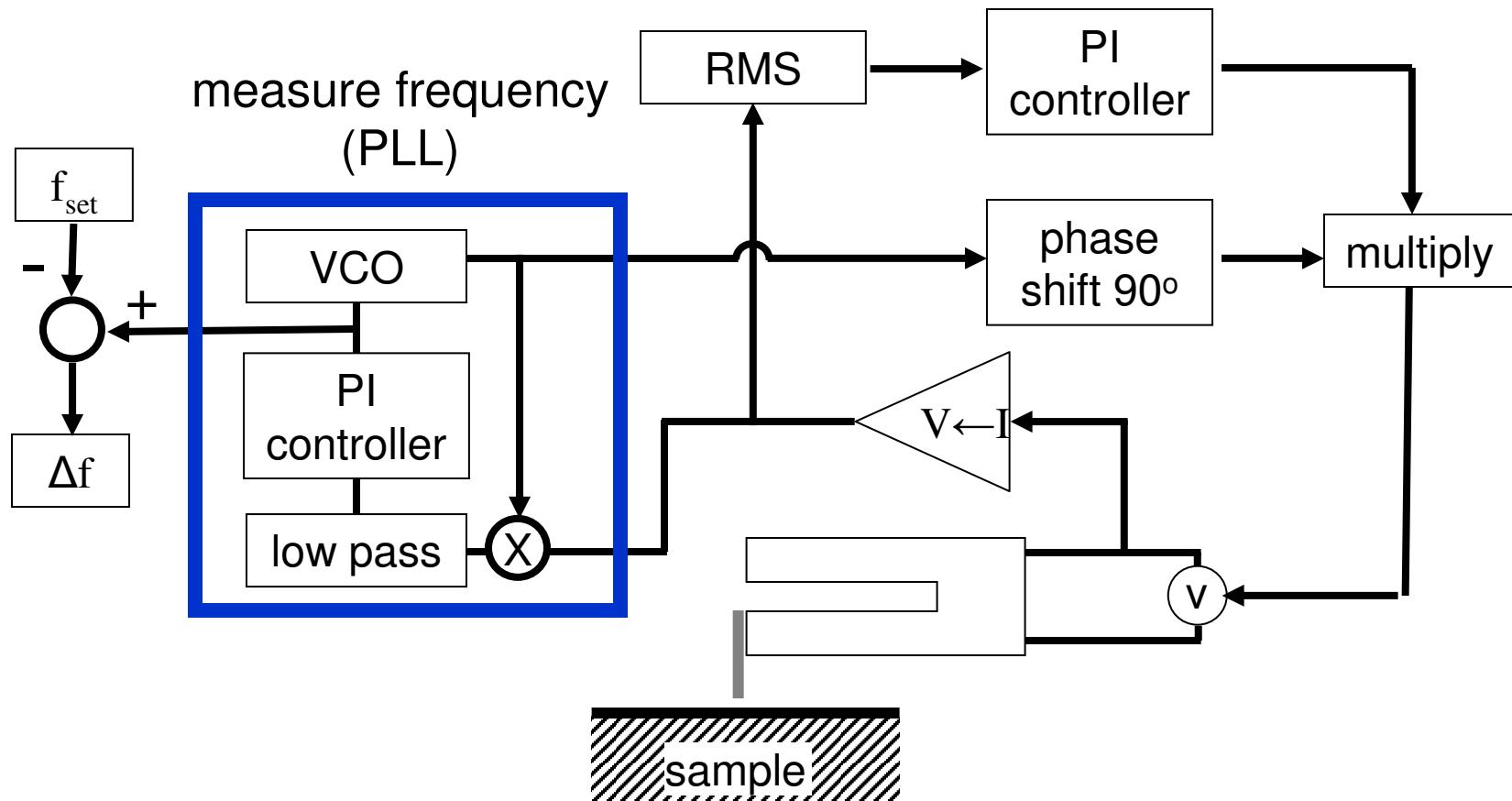
# Experimental Set-Up

## Tuning Fork & Mechanical Excitation



# Experimental Set-Up

## Electrical Excitation-Variation



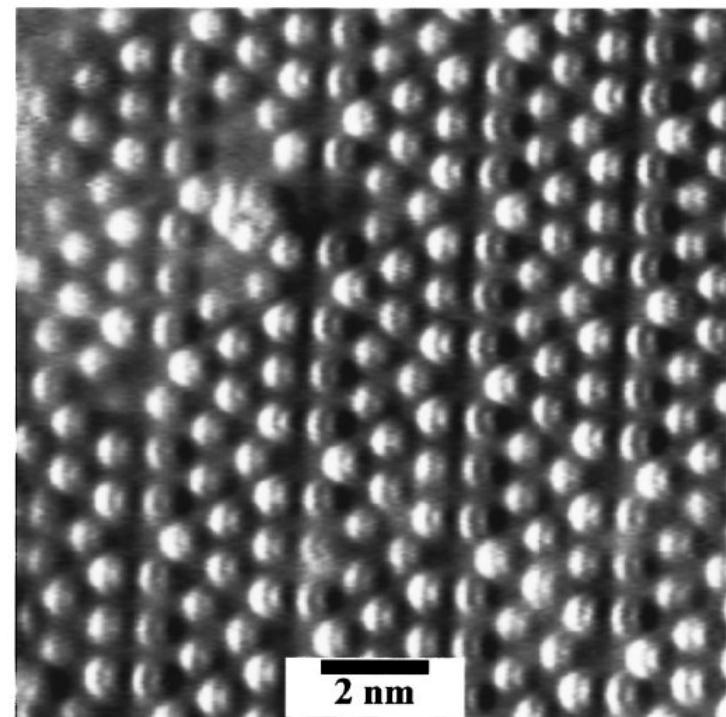
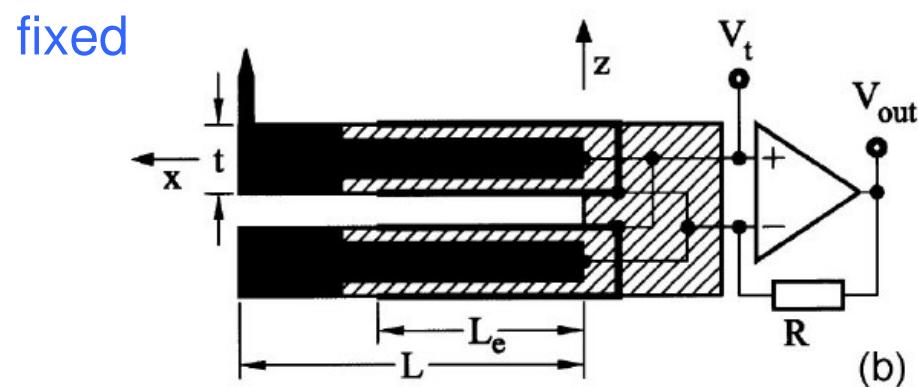
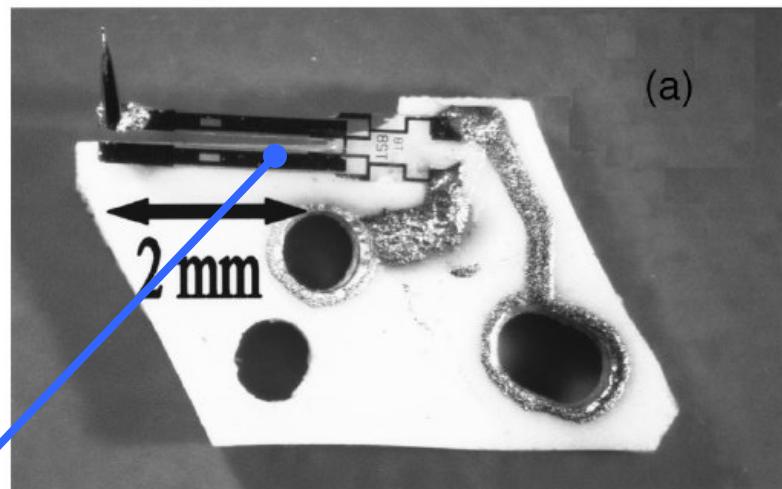
# Tuning Fork

## Mechanical vs. Electrical

- Mechanical
  - simpler electronics
  - marginally improved S/N
- Electrical
  - no dither piezo
  - eliminate one gluing step

# Mechanical Excitation

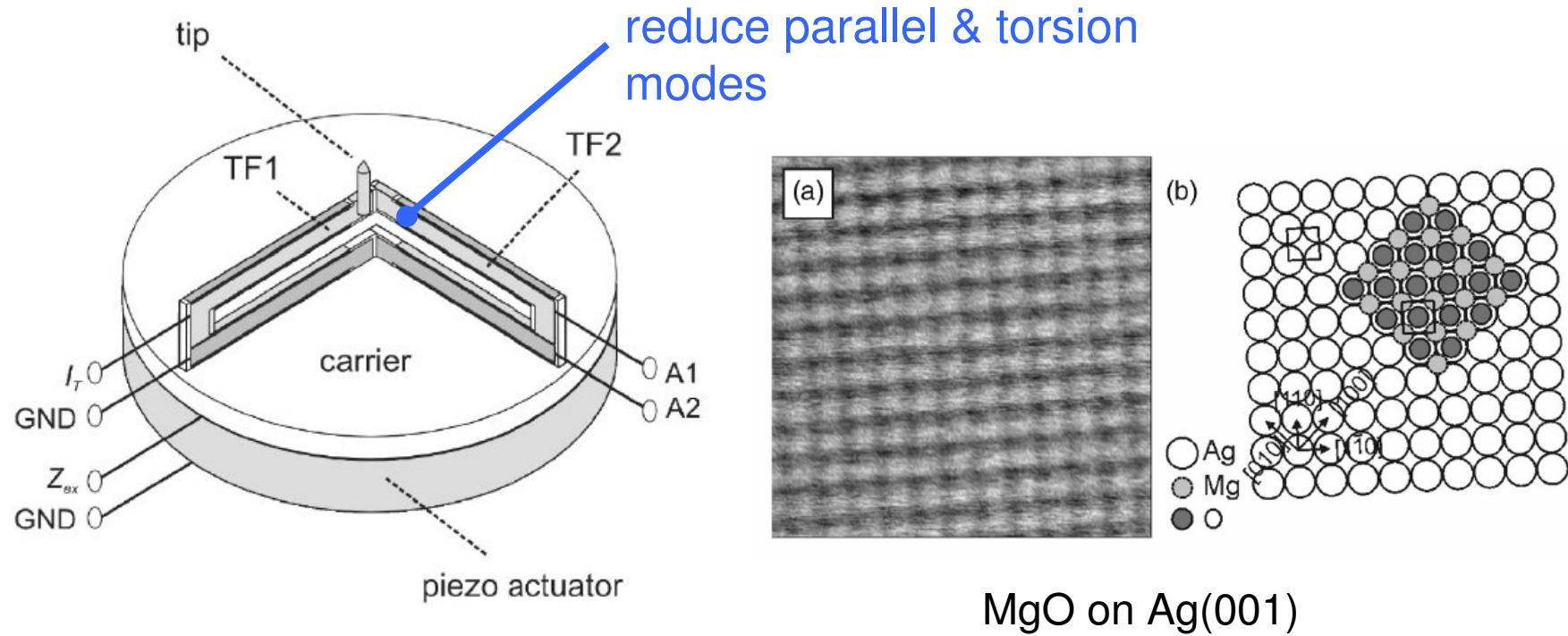
## Atomic Resolution



Giessibl FJ APPLIED PHYSICS LETTERS 76 (11): 1470-1472 MAR 13 2000

# Mechanical Excitation

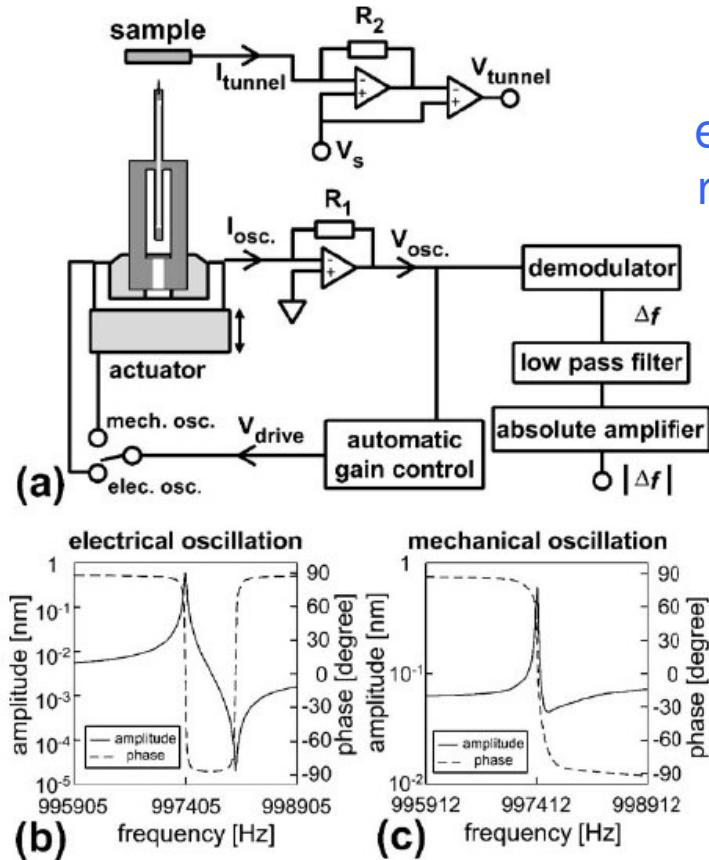
## Atomic Resolution



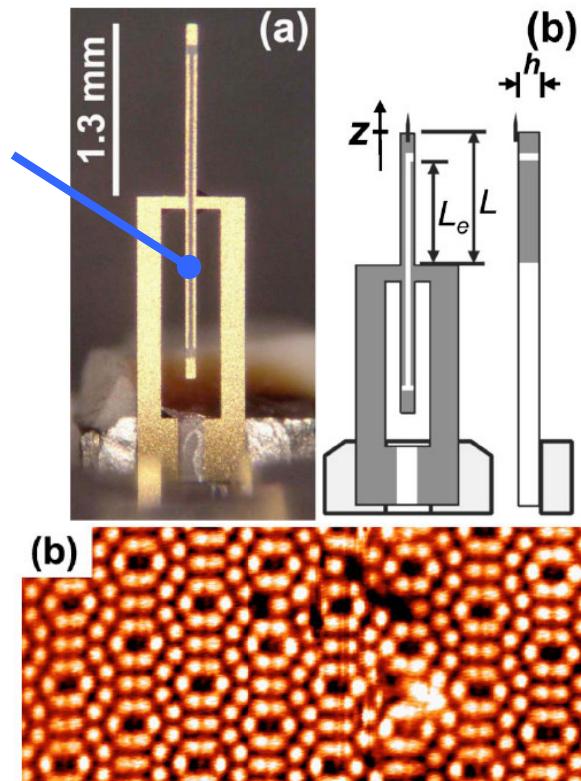
Heyde M, Sterrer M, Rust HP, et al. APPLIED PHYSICS LETTERS 87, 083104 2005

# Electrical Excitation

## Atomic Resolution



quartz  
length-  
extension  
resonator



Si(111)-(7x7)

# References

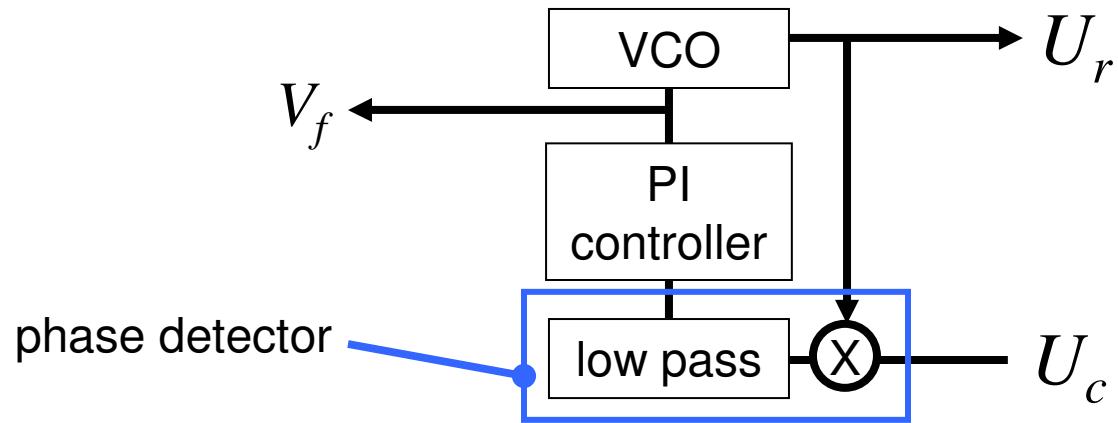
Giessibl, F.J. Rev. Mod. Phys., Vol. 75, No. 3, July 2003

Rychen, J., *et al.*, Rev. Sci. Instrum., Vol. 71, No. 4, April 2000

Loppacher, Ch., *et al.*, Appl. Phys. A 66, S215-218 (1998)

# Phase Locked Loop

## Details



$$U_c = \hat{U}_c \sin(\omega_c t + \varphi_c); \quad U_r = \hat{U}_r \cos(\omega_r t + \varphi_r)$$

$$U_c U_r = \frac{\hat{U}_c \hat{U}_r}{2} [\sin((\omega_c - \omega_r)t + (\varphi_c - \varphi_r)) + \sin((\omega_c + \omega_r)t + (\varphi_c + \varphi_r))]$$

locked PLL  $\Rightarrow \omega_c - \omega_r = 0$  & low-pass filter

$$U_c U_r \cong \frac{\hat{U}_c \hat{U}_r}{2} \sin(\varphi_c - \varphi_r) \cong K_d \Delta \varphi$$